

## 120V N-Channel Enhancement Mode MOSFET

### Description

The AP90N12D uses advanced **SGT II** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 7.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 120V$   $I_D = 90A$

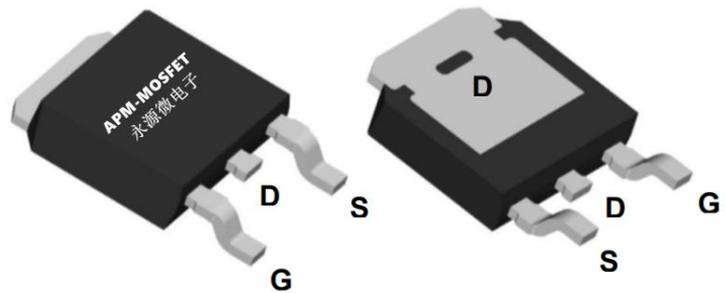
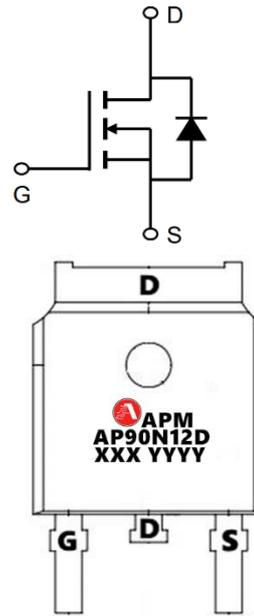
$R_{DS(ON)} < 9.0m\Omega @ V_{GS}=10V$  (Type: **7.5m $\Omega$** )

### Application

Mobile phone fast charging

Brushless motor

Home appliance control board



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP90N12D	TO-252-3L	AP90N12D XXXX YYYY	2500

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain source voltage	120	V
$V_{GS}$	Gate source voltage	$\pm 20$	V
$I_D @ T_A=25^\circ\text{C}$	Continuous drain current <sup>1)</sup> , $T_C=25^\circ\text{C}$	90	A
$I_D @ T_A=70^\circ\text{C}$	Continuous drain current <sup>1)</sup> , $T_C=75^\circ\text{C}$	35	A
$I_{DM}$	Pulsed drain current <sup>2)</sup> , $T_C=25^\circ\text{C}$	270	A
$P_D$	Power dissipation <sup>3)</sup> , $T_C=25^\circ\text{C}$	160	W
EAS	Single pulsed avalanche energy <sup>4)</sup>	125	mJ
Tstg, $T_j$	Operation and storage temperature	-55 to 150	$^\circ\text{C}$
$R_{\theta JC}$	Thermal resistance, junction-case	0.89	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal resistance, junction-ambient <sup>5)</sup>	62.5	$^\circ\text{C/W}$



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### Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	120	135	-	V
IGSS	Gate-body Leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	$\pm 100$	nA
IDSS $T_J=25^\circ\text{C}$	Zero Gate Voltage Drain Current	$V_{DS} = 120V, V_{GS} = 0V$	-	-	1	$\mu A$
IDSS $T_J=100^\circ\text{C}$			-	-	100	
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.5	2.0	2.5	V
RDS(on)	Drain-Source on-Resistance <sup>4</sup>	$V_{GS} = 10V, I_D = 20A$	-	7.5	9.0	m $\Omega$
		$V_{GS} = 4.5V, I_D = 10A$	-	9.0	12	
gfs	Forward Transconductance <sup>4</sup>	$V_{DS}=10V, I_D=20A$	-	75	-	S
Ciss	Input Capacitance	$V_{DS} = 60V, V_{GS} = 0V,$ $f = 1\text{MHz}$	-	1854	-	pF
Coss	Output Capacitance		-	270	-	
Crss	Reverse Transfer Capacitance		-	10	-	
R <sub>g</sub>	Gate Resistance	$f = 1\text{MHz}$	-	2.3	-	$\Omega$
Q <sub>g</sub>	Total Gate Charge	$V_{GS} = 10V, V_{DS} = 60V,$ $I_D = 20A$	-	30	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	5.8	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	6	-	
td(on)	Turn-on Delay Time	$V_{GS} = 10V, V_{DD} = 60V, R_G =$ $3\Omega, I_D = 20A$	-	9.5	-	ns
t <sub>r</sub>	Rise Time		-	4.2	-	
td(off)	Turn-off Delay Time		-	27.2	-	
t <sub>f</sub>	Fall Time		-	6.6	-	
trr	Body Diode Reverse Recovery Time	$I_F = 20A, dI/dt = 100A/\mu s$	-	52	-	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	83.5	-	nC
VSD	Diode Forward Voltage <sup>4</sup>	$I_S = 20A, V_{GS} = 0V$	-	-	1.2	V
IS $T_C=25^\circ\text{C}$	Continuous Source Current	-	-	-	90	A

#### Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width .The EAS data shows Max. rating .
3. The power dissipation is limited by 175°C junction temperature
4. EAS condition:  $T_J=25^\circ\text{C}, V_{DD}=50V, V_{GS}=10V, L=0.1\text{mH}, I_{AS}=30A$
5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

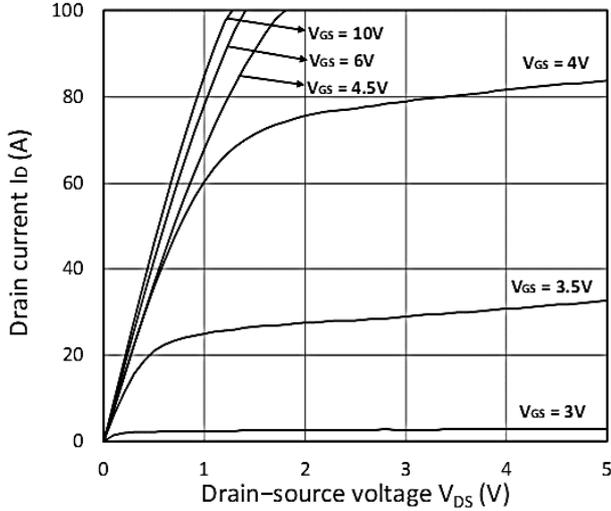


Figure 1. Output Characteristics

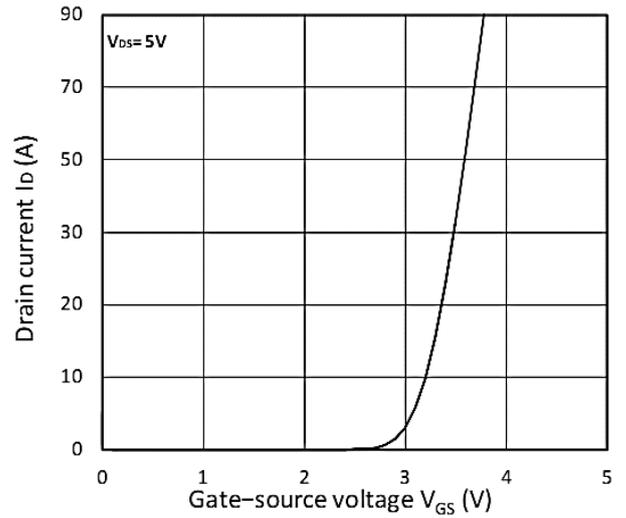


Figure 2. Transfer Characteristics

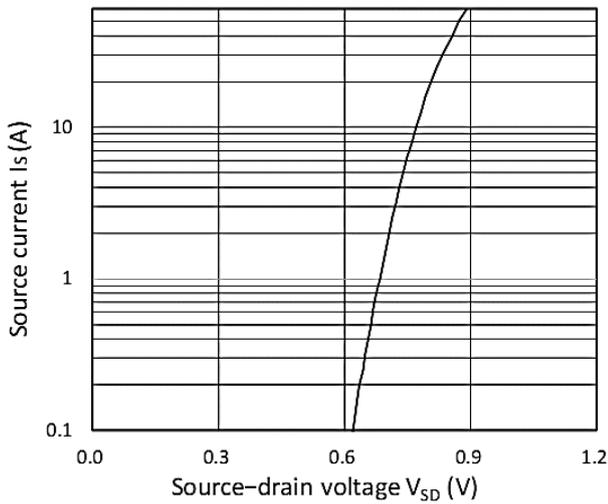


Figure 3. Forward Characteristics of Reverse

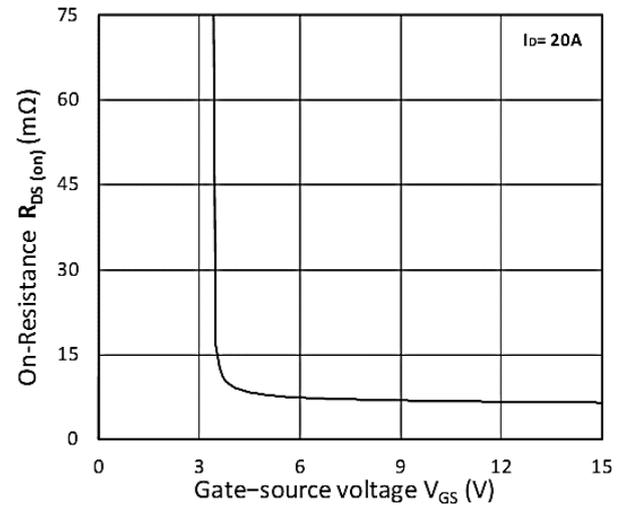


Figure 4.  $R_{DS(ON)}$  vs.  $V_{GS}$

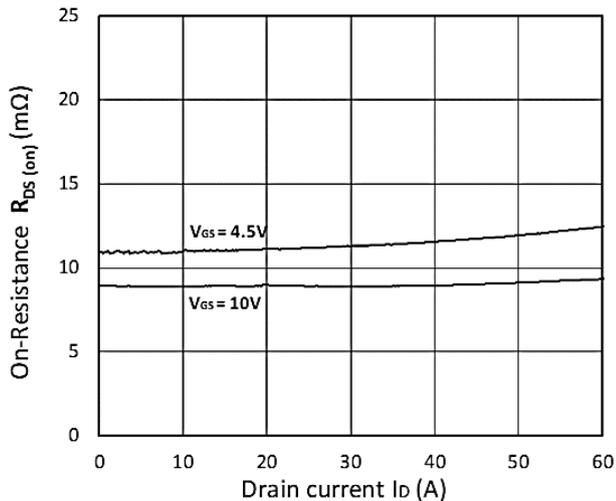


Figure 5.  $R_{DS(ON)}$  vs.  $I_D$

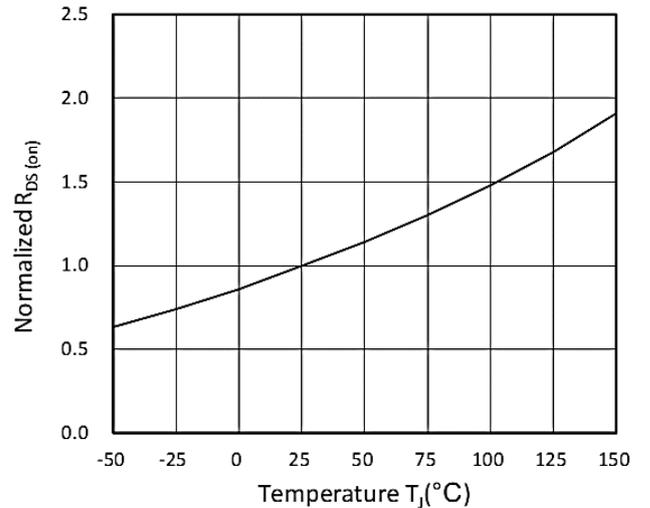
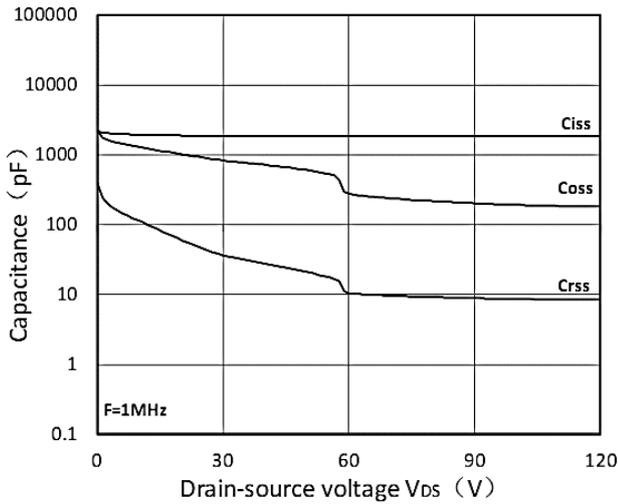
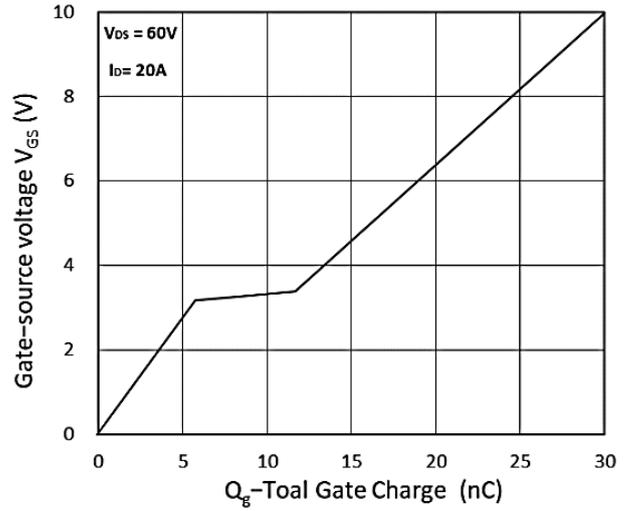


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

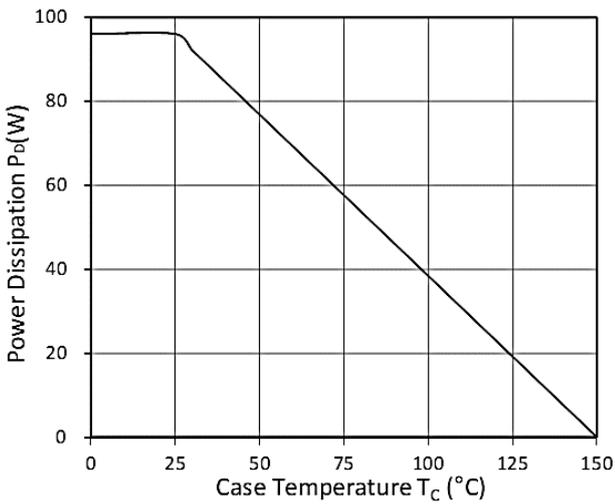
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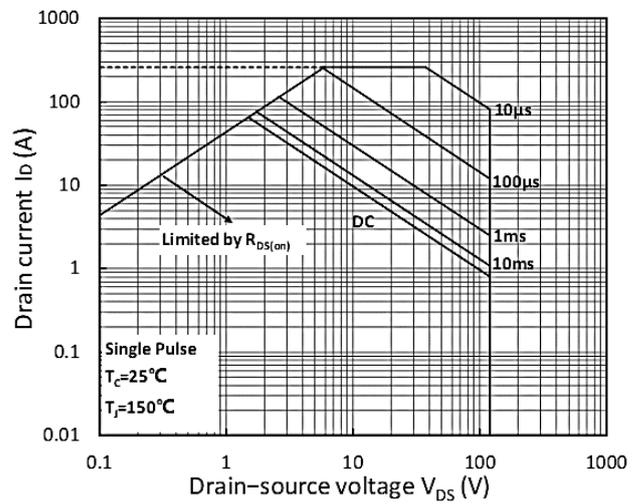
**Figure 7. Capacitance Characteristics**



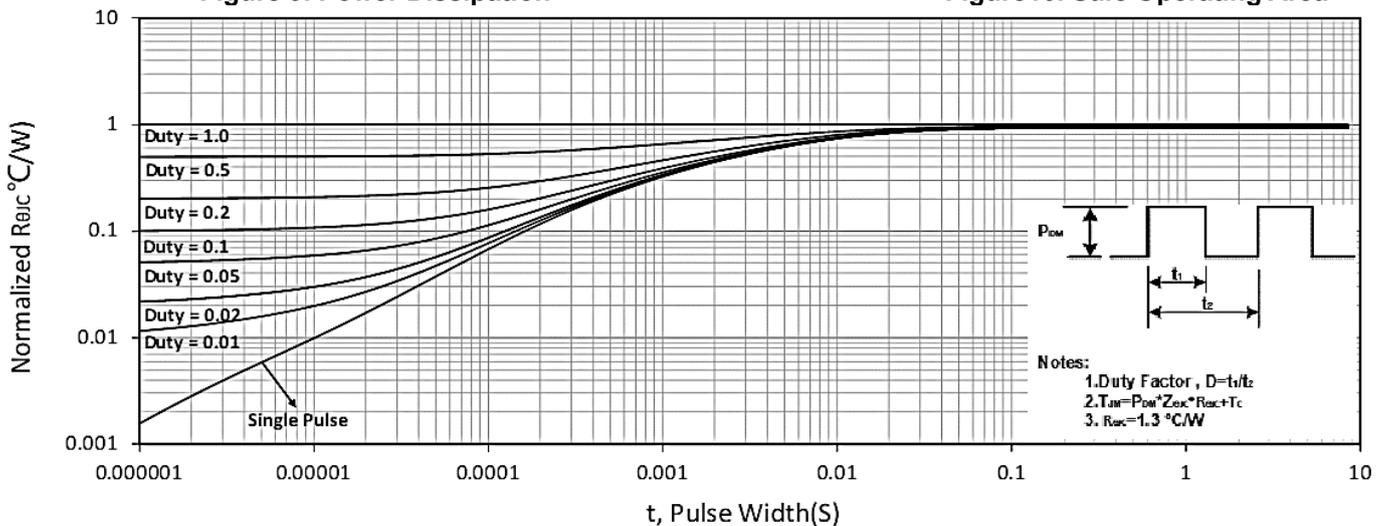
**Figure 8. Gate Charge Characteristics**



**Figure 9. Power Dissipation**

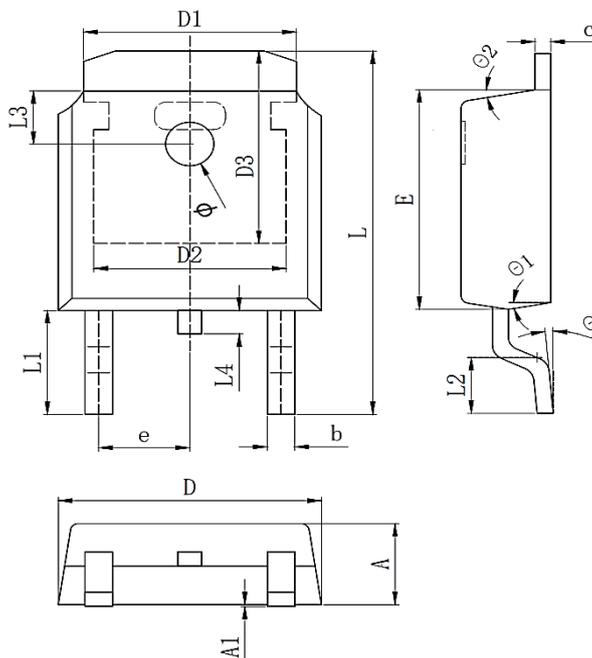


**Figure 10. Safe Operating Area**



**Figure 11. Normalized Maximum Transient Thermal Impedance**

### Package Mechanical Data-TO-252-3L



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3
θ	0°		10°
θ <sub>1</sub>	5°		10°
θ <sub>2</sub>	5°		10°

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Edition	Date	Change
REV1.0	2023/8/1	Initial release

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